

Title (en)

TESTING DEVICE FOR ELECTRICALLY TESTING AN ELECTRICAL TEST SPECIMEN

Title (de)

PRÜFVORRICHTUNG ZUR ELEKTRISCHEN PRÜFUNG EINES ELEKTRISCHEN PRÜFLINGS

Title (fr)

DISPOSITIF D'ESSAI PERMETTANT L'ESSAI ÉLECTRIQUE D'UN ÉCHANTILLON ÉLECTRIQUE

Publication

EP 3014287 A1 20160504 (DE)

Application

EP 14725018 A 20140415

Priority

- DE 102013010934 A 20130629
- EP 2014057671 W 20140415

Abstract (en)

[origin: WO2014206594A1] The invention relates to a testing device (1) for electrically testing an electrical test specimen (2), in particular a wafer, said testing device having a test head (4) in which at least one testing contact (5) is mounted for electrically contacting the test specimen (2). At least one outlet opening (13) for discharging a gas, in particular a protective gas, is provided in a wall (15) of the test head (4) in a contact region (14).

IPC 8 full level

G01R 1/04 (2006.01); **G01R 31/28** (2006.01)

CPC (source: EP US)

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Citation (search report)

See references of WO 2014206594A1

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Designated extension state (EPC)

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